

# Testbench and CERN 07 analysis reloaded

LPNHE SiLC team

SiLC 2008

CERN, July 2nd, 2008

## Outline:

Testbench studies Nov. 2007-April 2008

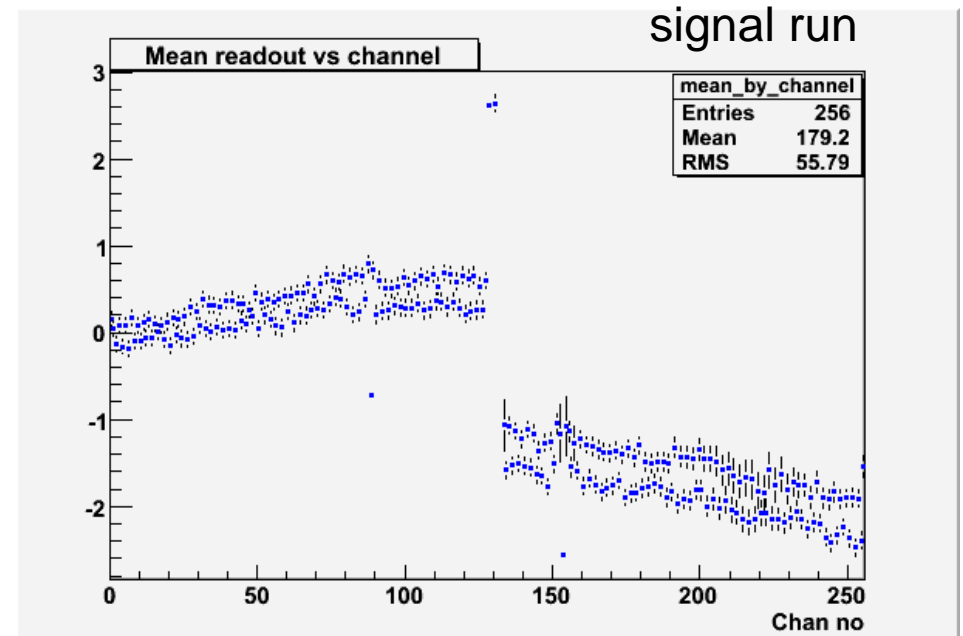
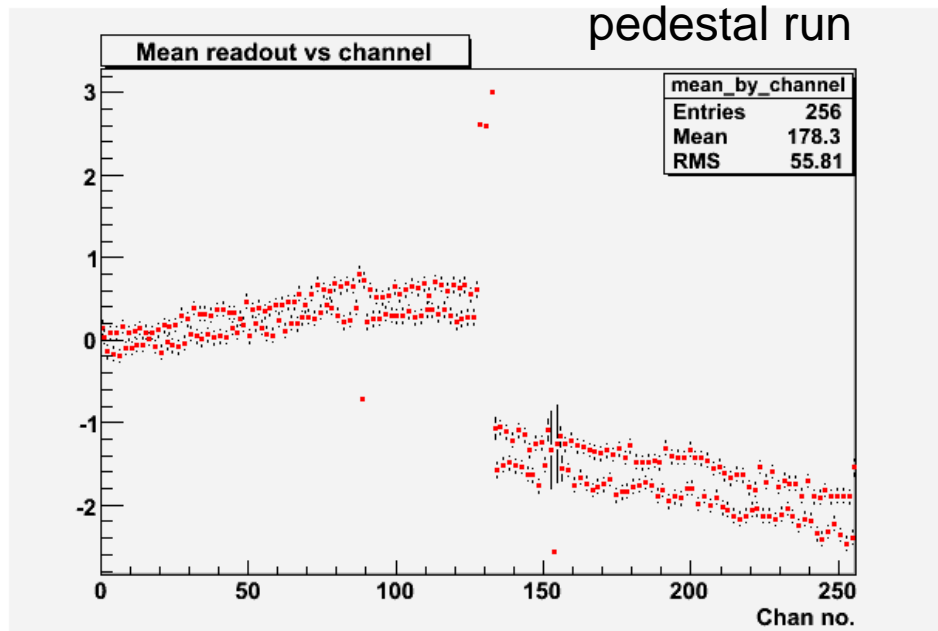
CERN testbeam Oct. 2007

# Introduction

- New testbench tests (with source)
- New analysis software
  - Simple analysis code written by Catalin available on the internal page
    - Couldn't figure out the old code so wrote a new one
    - Extra work=bad, Independent cross-check = good
  - More OO-evolved analysis code (GUI and all) written by Alexandre and to be embellished by me will replace the above
- More detail about testbench hardware in Jacques David and Alexandre Charpy's talks
- This talk:
  - Testbench and CERN testbeam VA1
  - Testbench and CERN testbeam 130 nm (cms) 130 nm (hpk)

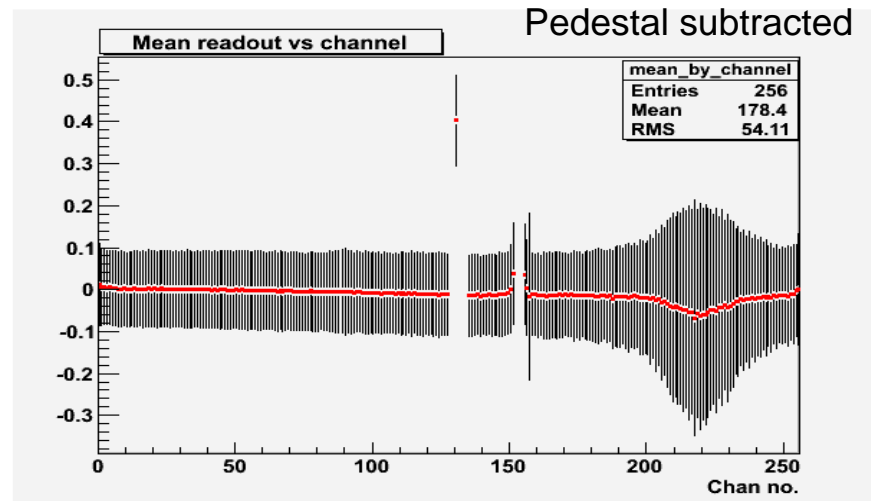
# Testbench VA1

- At the minimum, the analysis code should
  - Plot the mean readout for all channels
  - Pedestal and common-noise subtraction
  - Signal/Background for each channel
  - S/N versus channel
- At the maximum, the analysis should show correlation among multiple detectors as tracks pass them through.

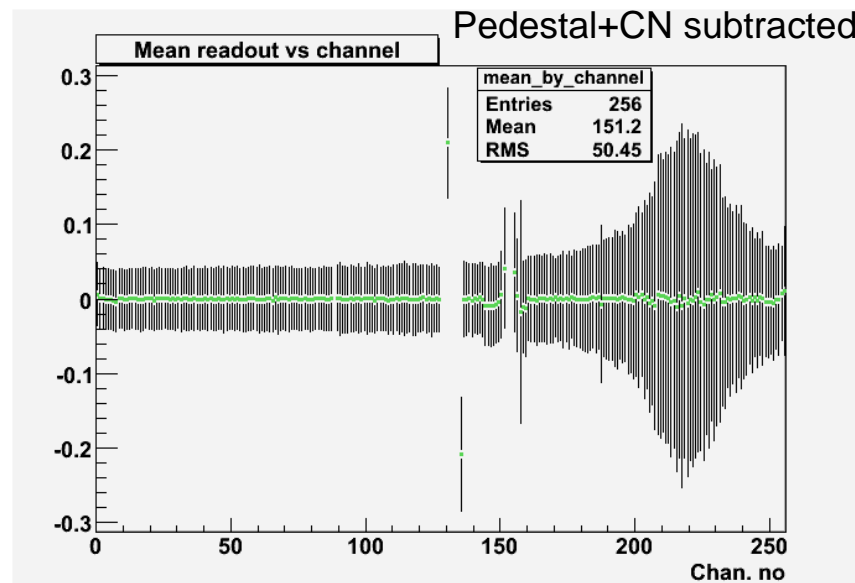


# Testbench VA1 (cont'd)

- Take every signal run event and subtract average pedestal

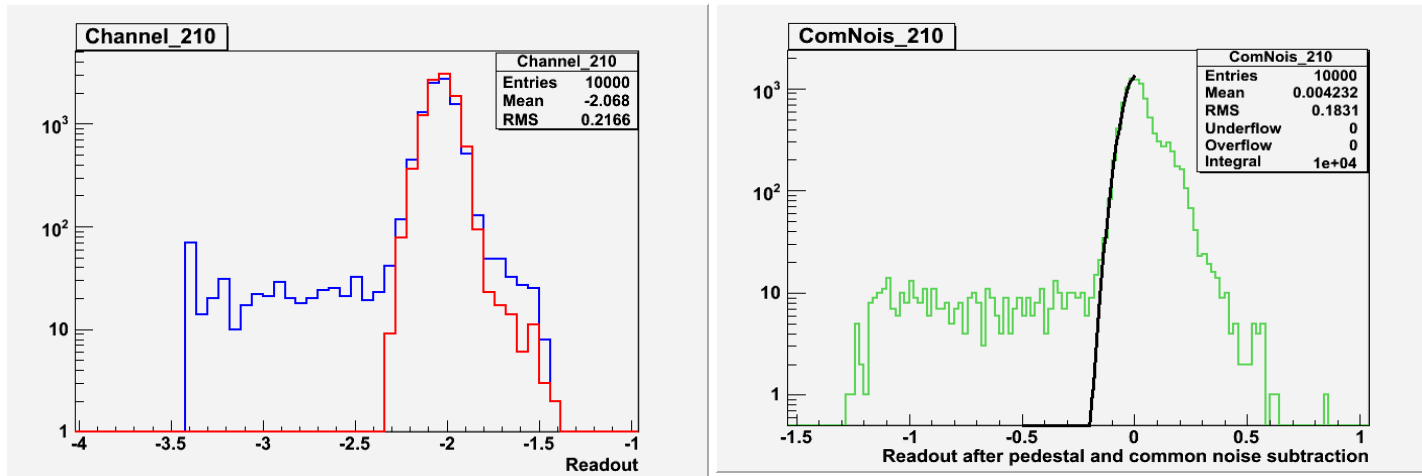


- Take every signal run event and subtract average pedestal+CN

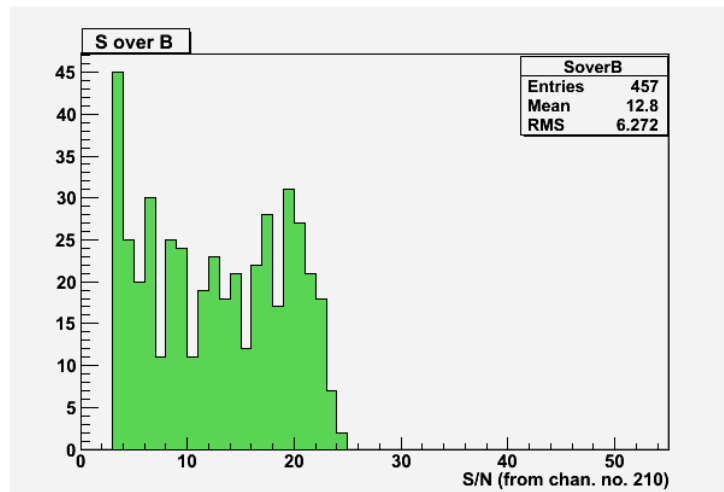


# Testbench VA1: S/N?

- Take a channel (say 210). Plot the readout red = ped. blue = sig.
- Plot the pedestal+CN subtracted readout, use a Gauss fit

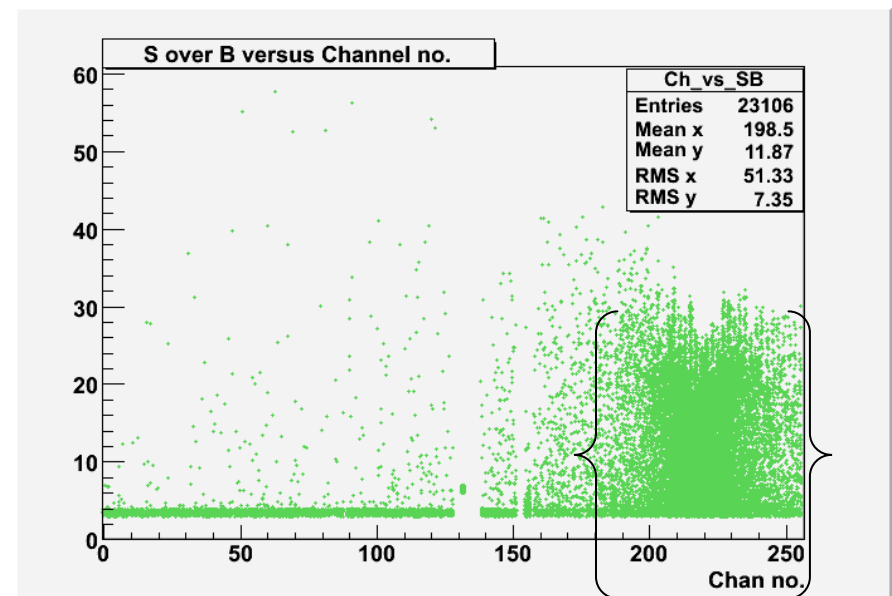
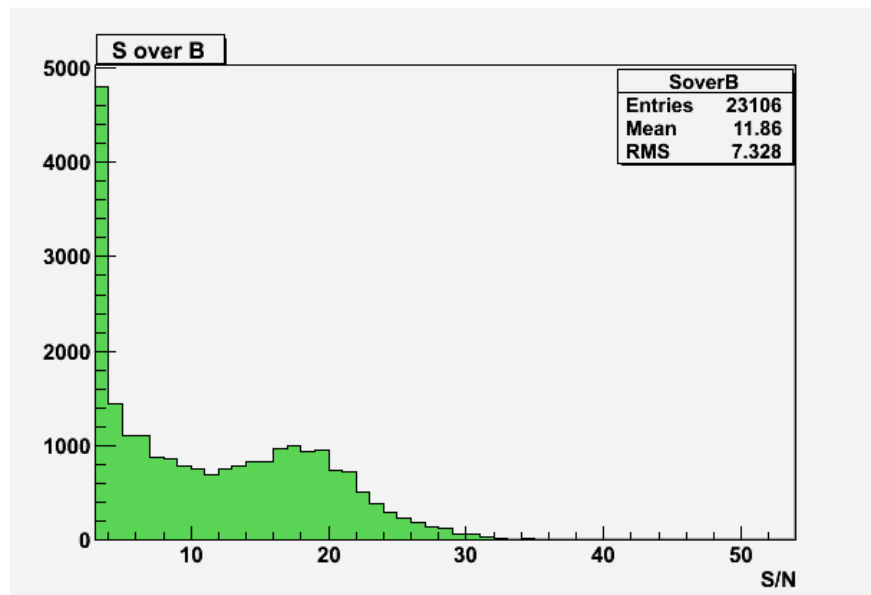


- For every event which falls outside the  $N\sigma$  interval from the Gauss mean, compute  $(\text{readout} - \sigma) / (\sigma/2)$ . Histogram it and plot it.



# Testbench VA1: S/N?

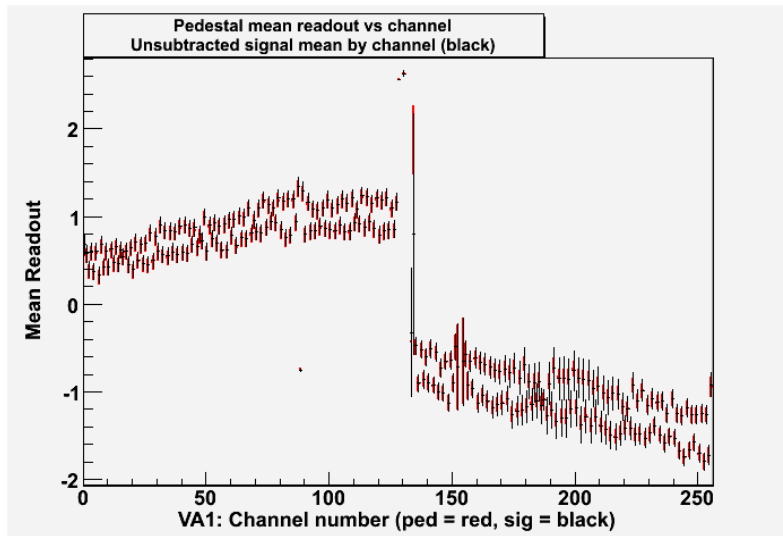
- That was for one channel (210). Now do the same for all channels:



- Conclusion:  $S/N \cong 18$       { } = channels closer to source
- Great. How about testbeam data?

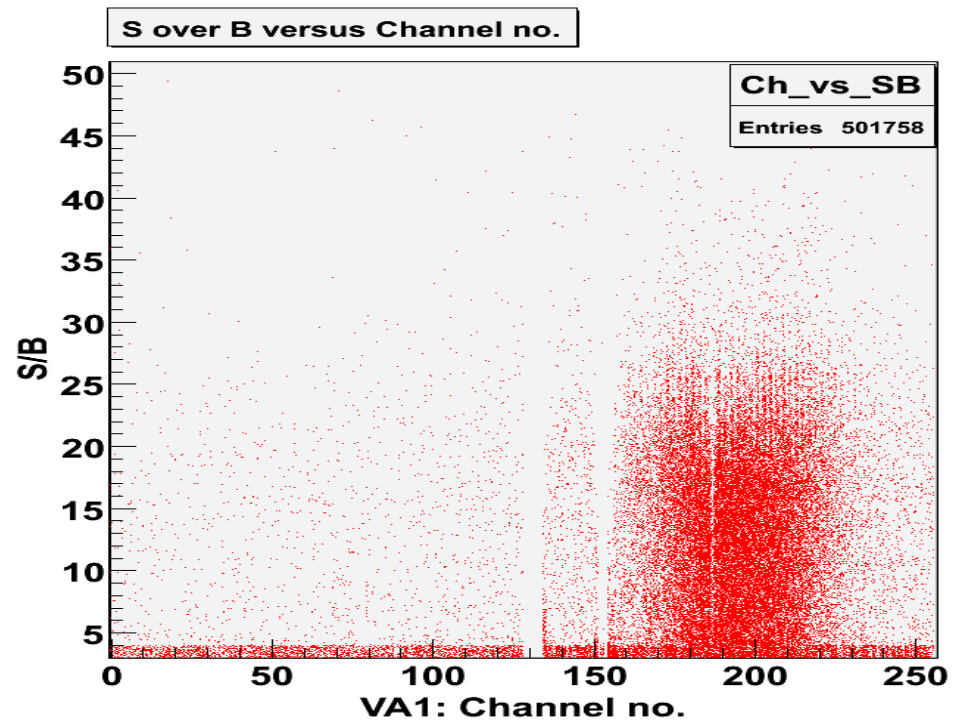
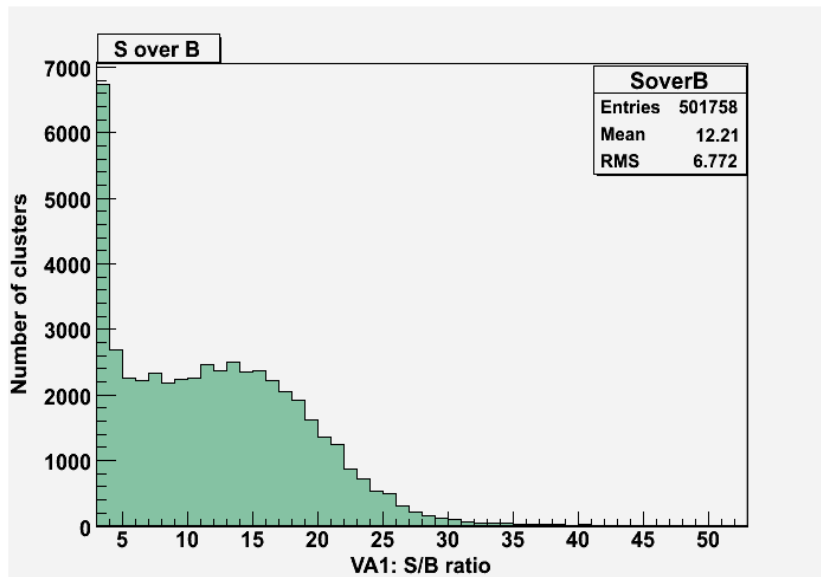
# Oct 2007 Testbeam VA1

- Same analysis template (recipe)



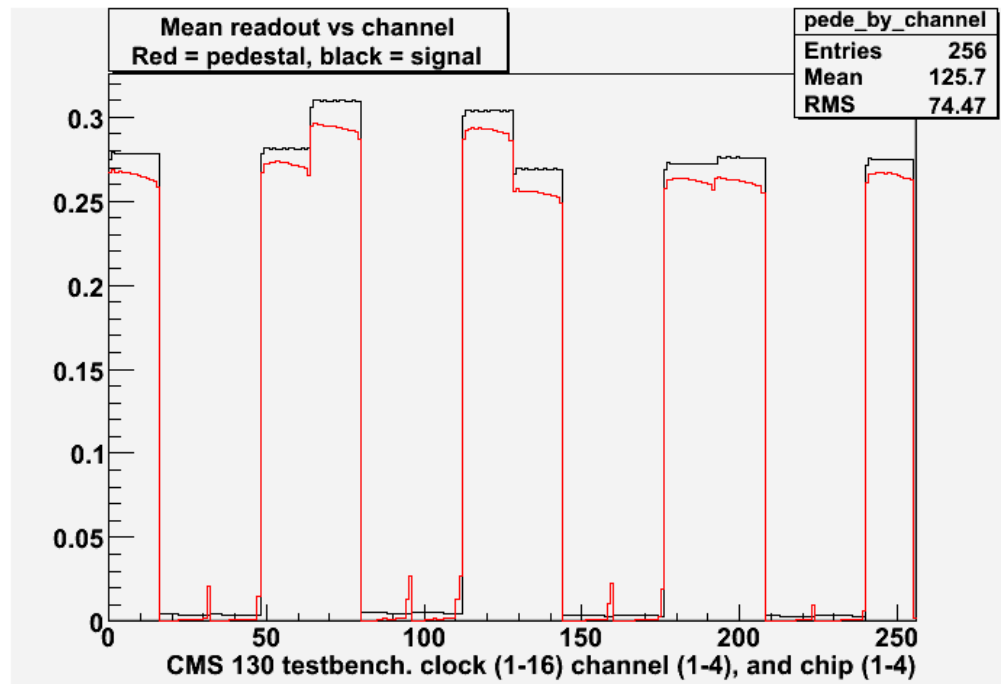
All analysis results compare well with the testbench results.

- Signal / Noise – all channels



# Testbench 130 nm + “cms”

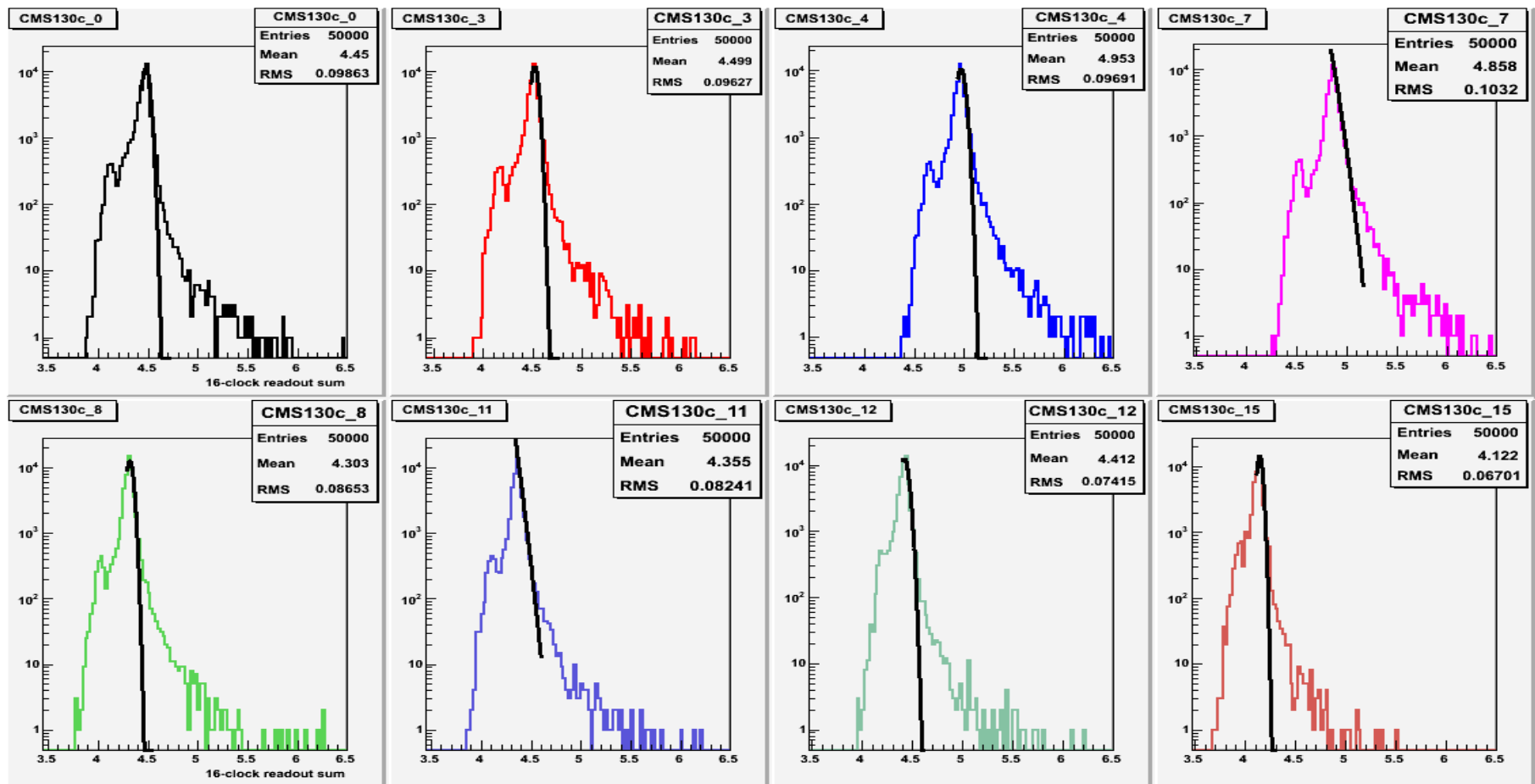
- Four chips of four channels each:
  - Two channels unwired per chip leave 8 working channels
- Readout from each chip sampled 16 times (16 “clocks”)
  - 4 chips x 2 chan x 16 clocks = 128 readout values / event
- Plot the pedestal / signal run mean readout vector





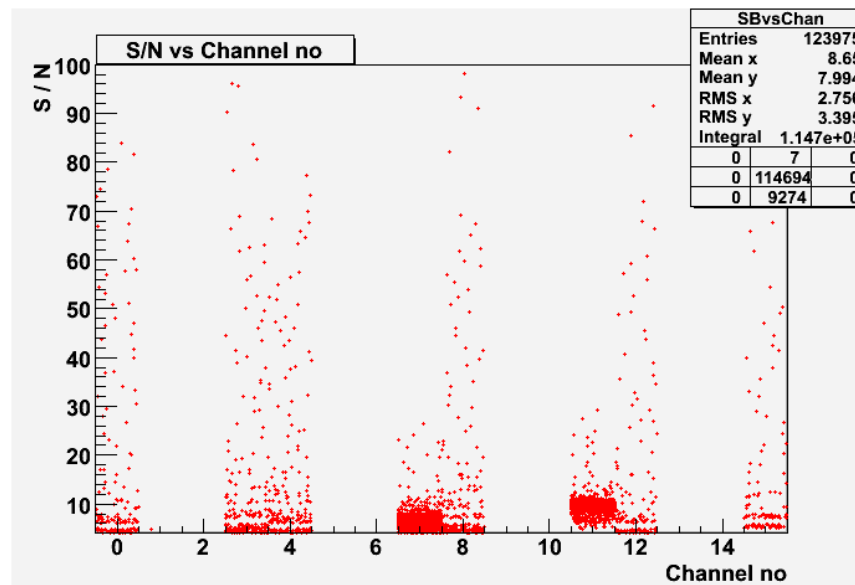
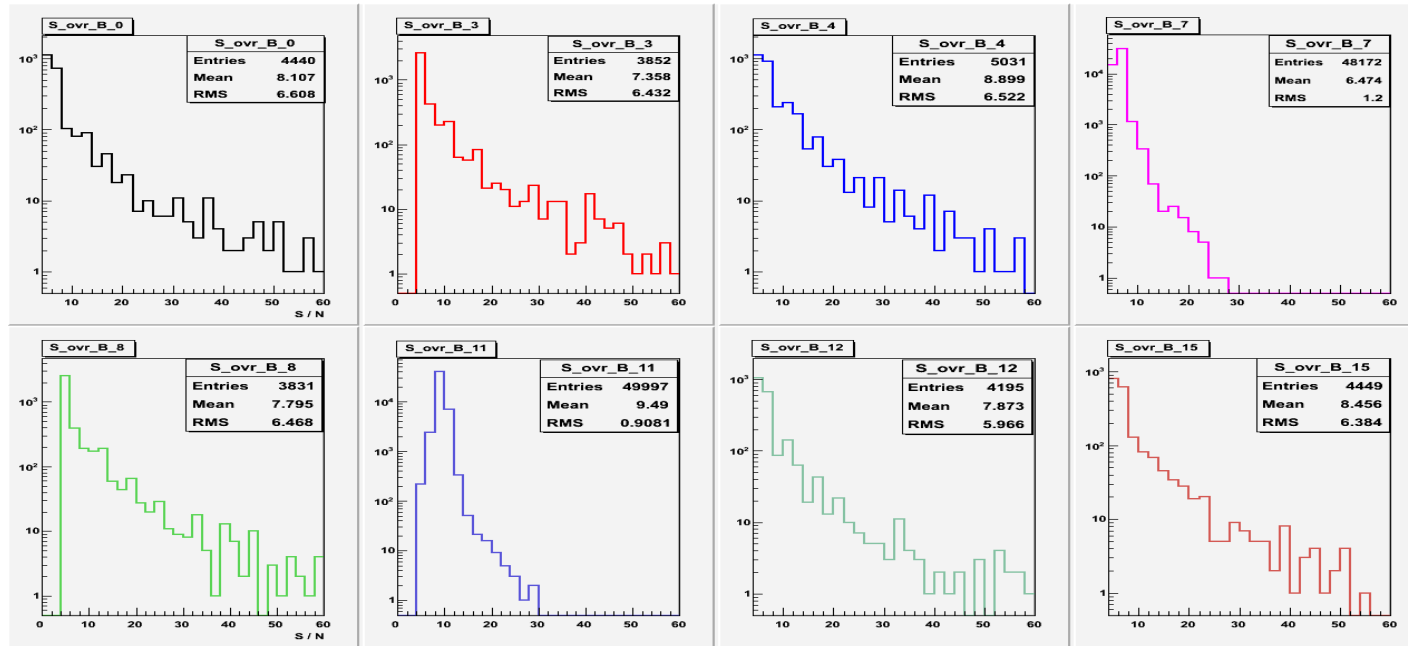
# Testbench 130 nm + “cms”

- 16-clock sum (mean) readout distributions for each channel
- Comparable across the 8 channels (4.1 – 4.9 range)
- Fit \*unsubtracted\* readout high tails with Gaussians



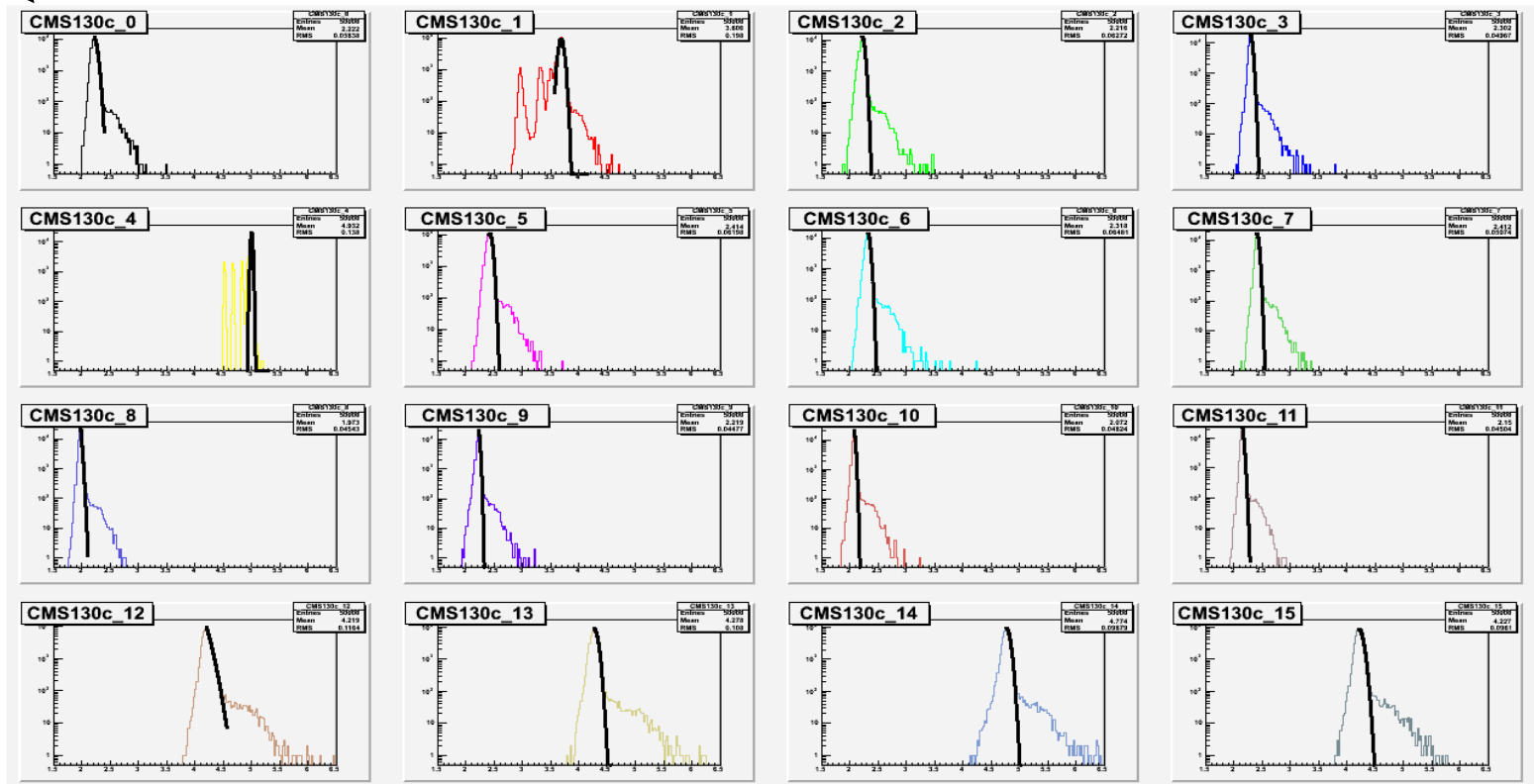
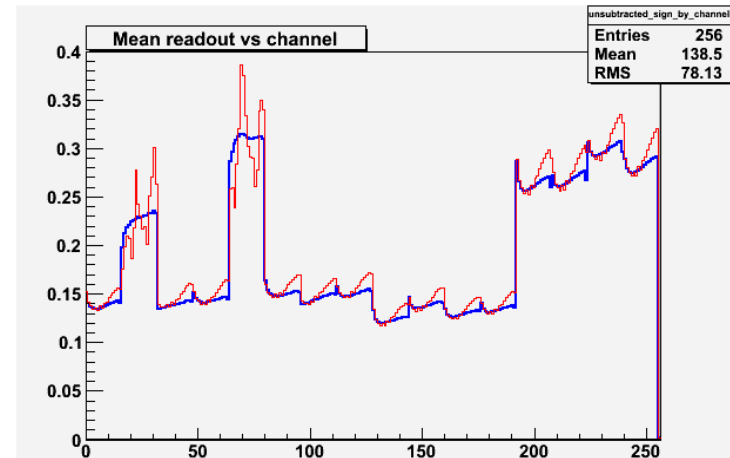
# Testbench 130 nm + "cms"

- Signal to noise distributions by channel



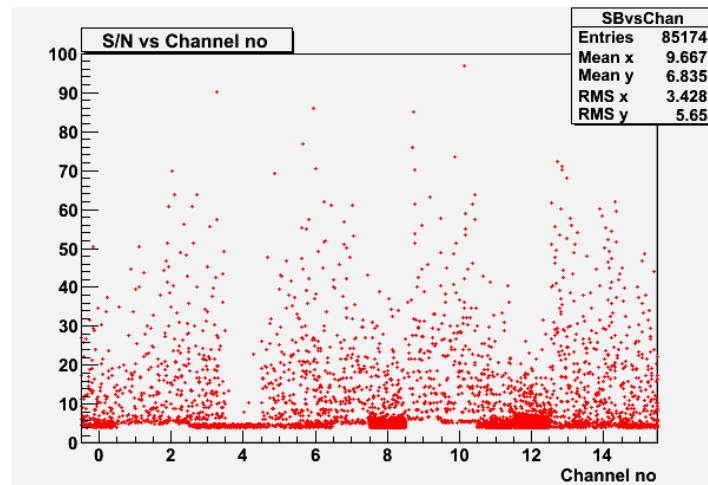
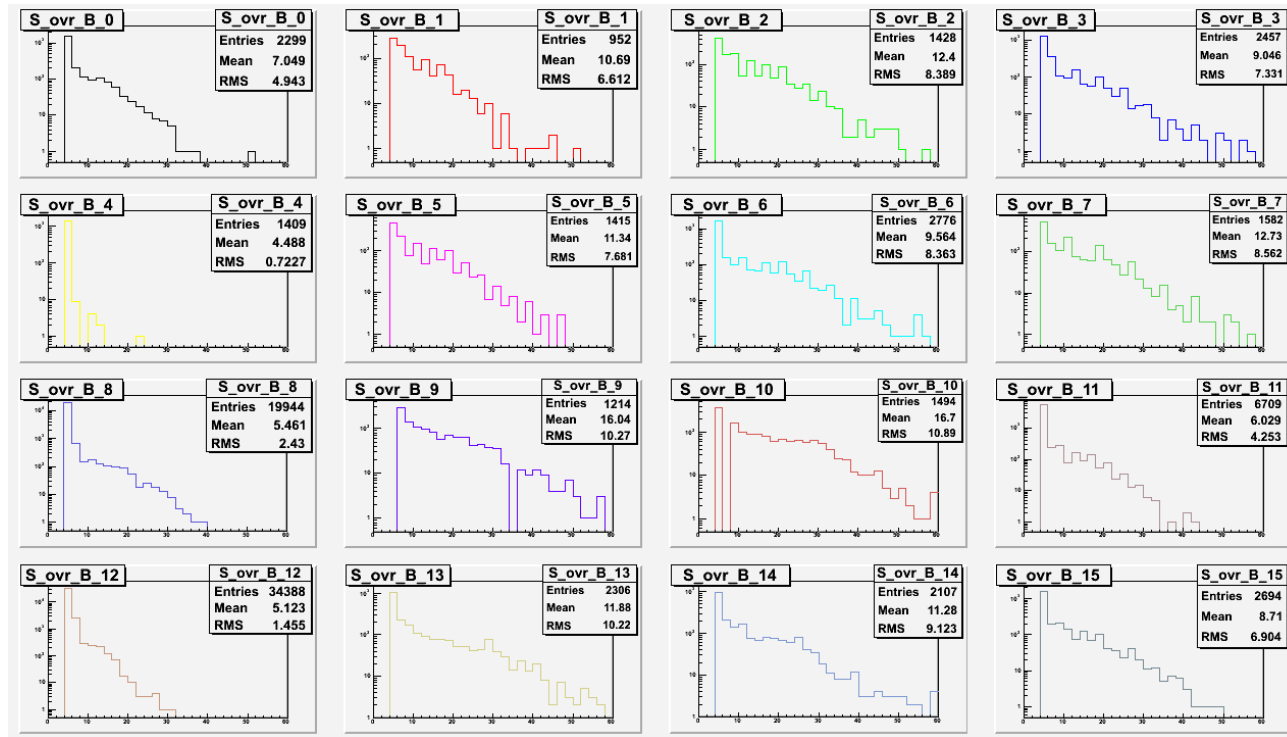
# Testbench 130 nm + “hpk”

- All channels wired in:
    - 4chip x 4chan x 16clk = 256
  - Look at mean(sum) readout
- For each channel of each chip  
Labels are wrong! cms ->hpk



# Testbench 130 nm + "hpk"

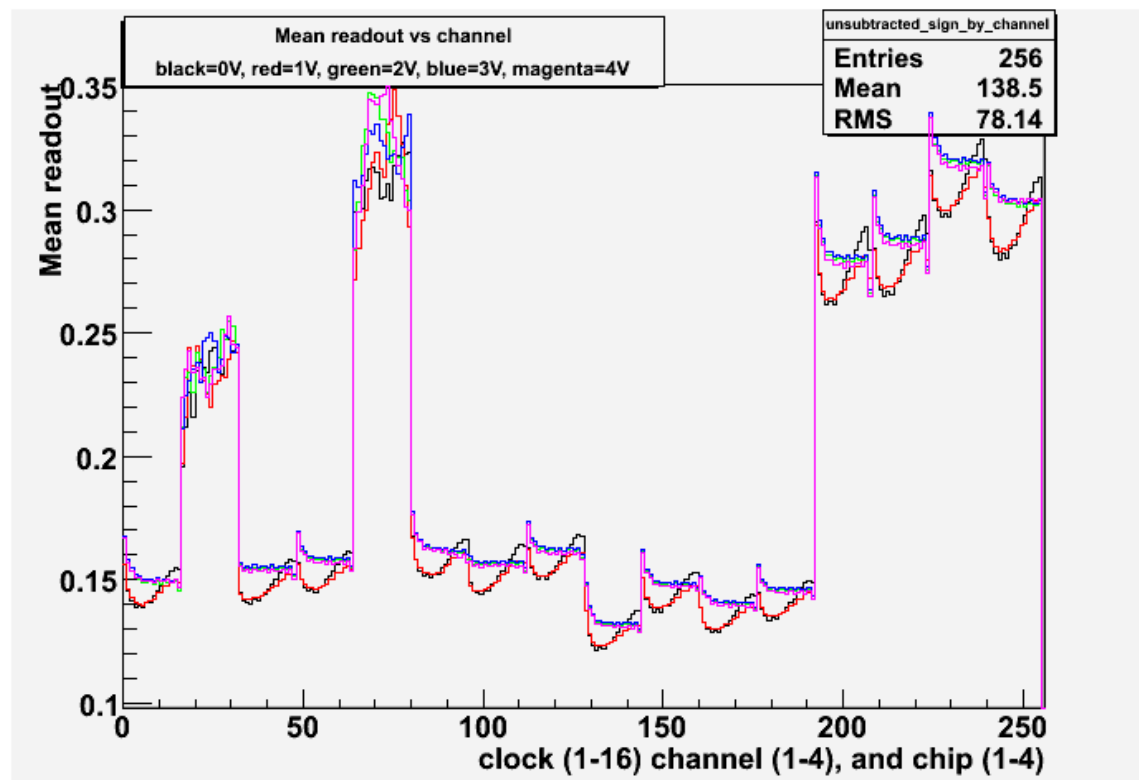
- Signal to noise distributions by channel



# Use shape info?

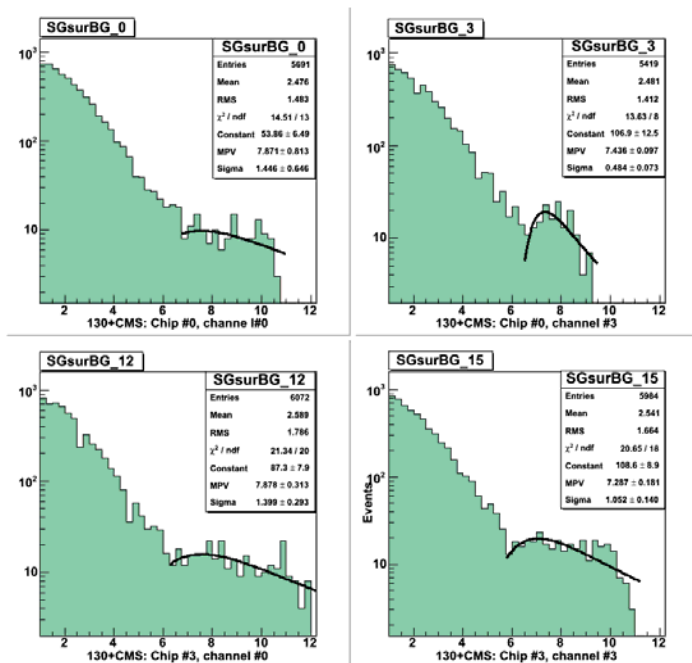
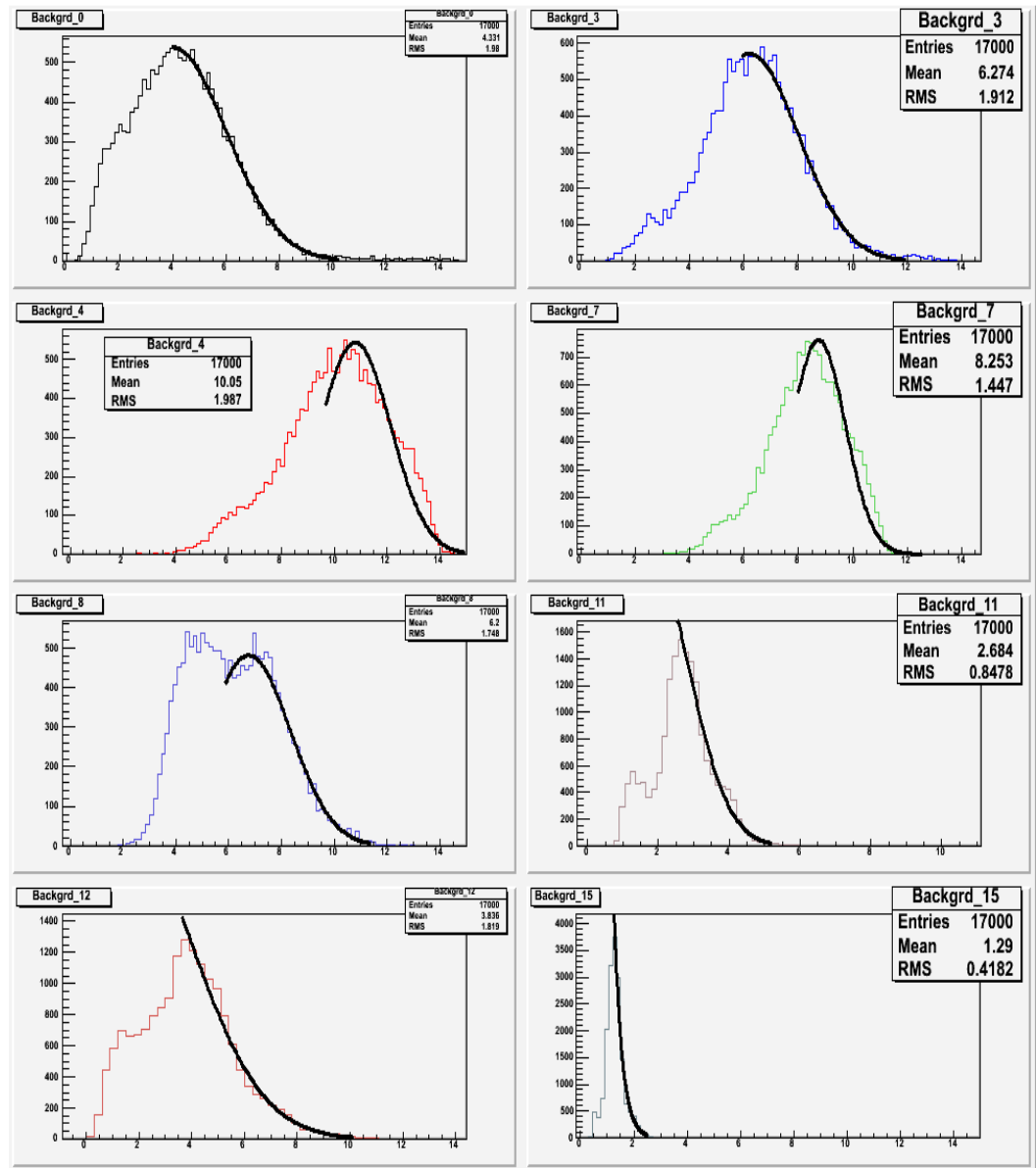
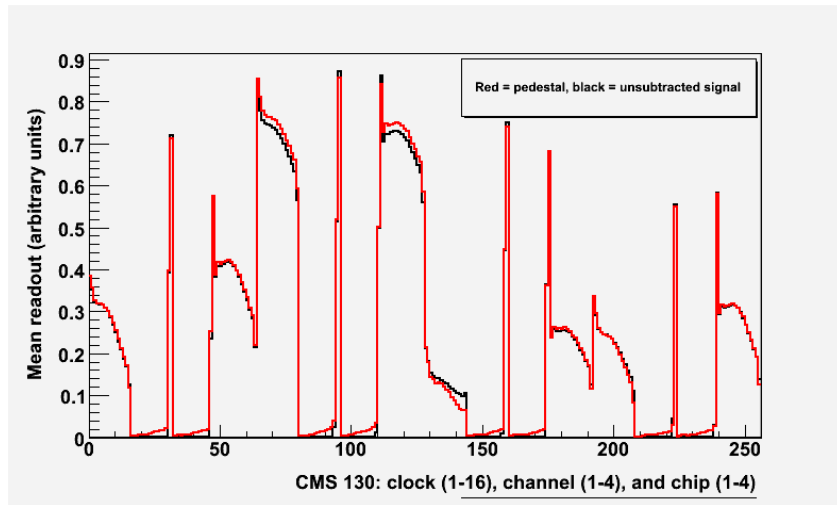
Possible to use the signal shape to improve noise rejection

Opted not to do this as the CERN data show similar shapes for S and B

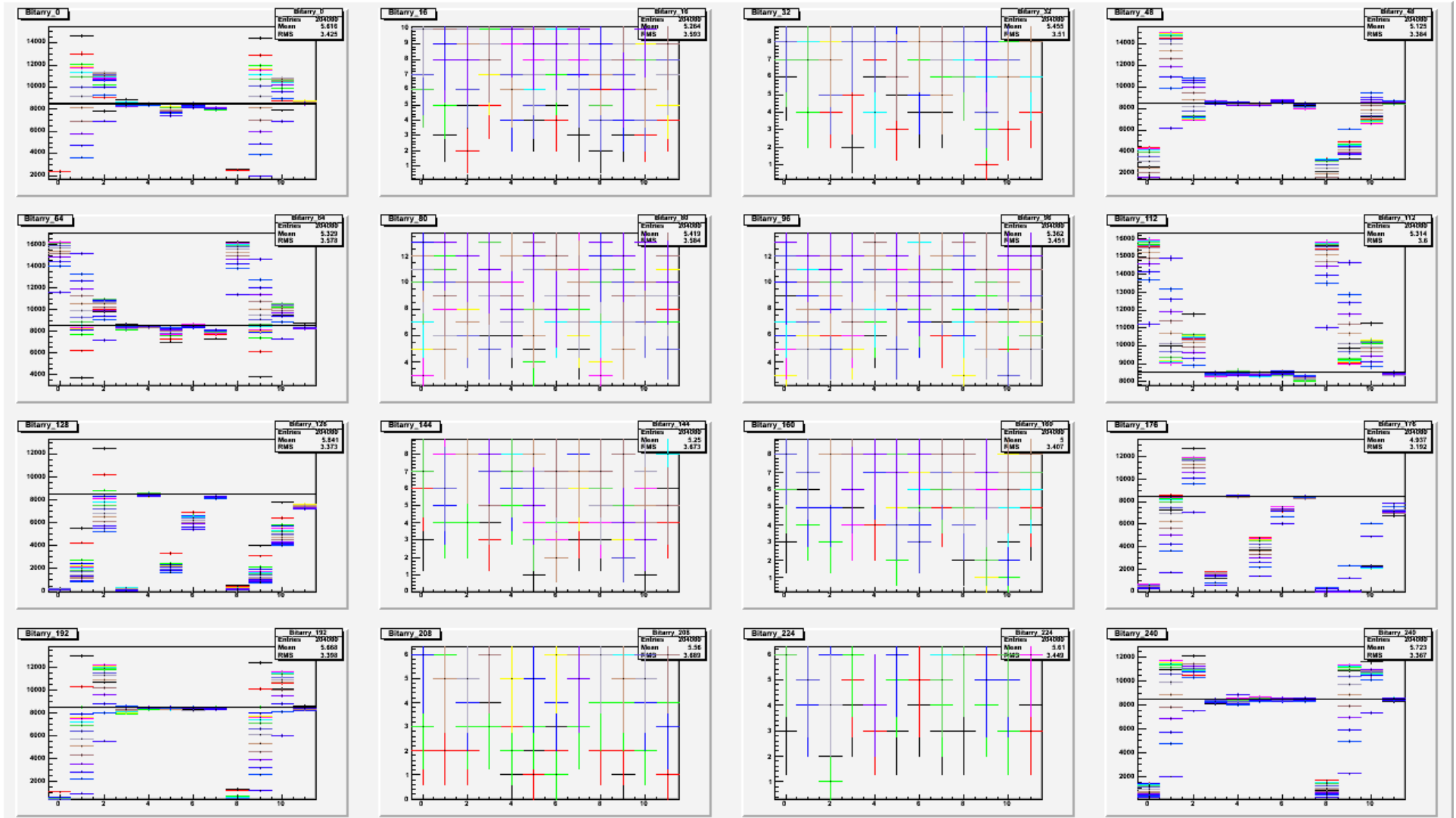


# CERN 07 testbeam (130 nm+cms)

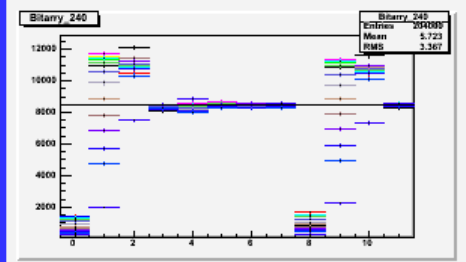
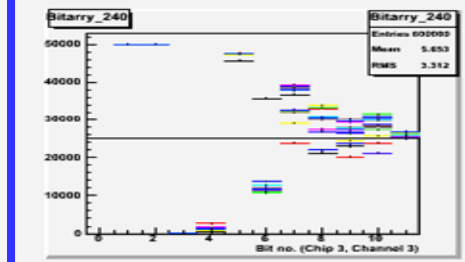
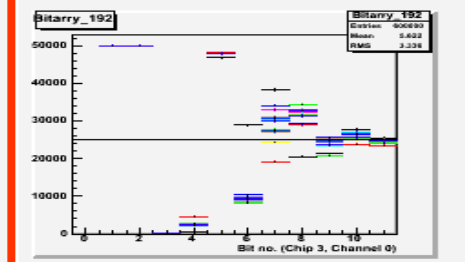
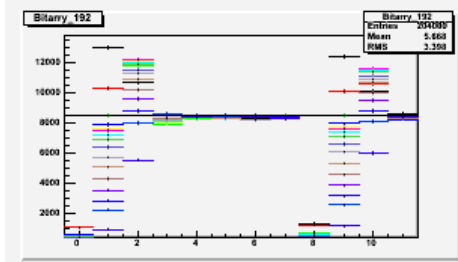
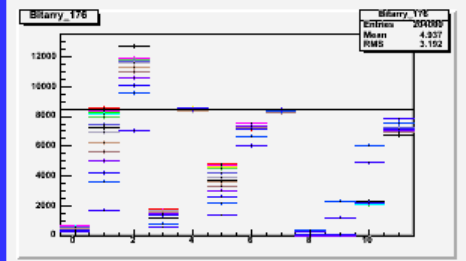
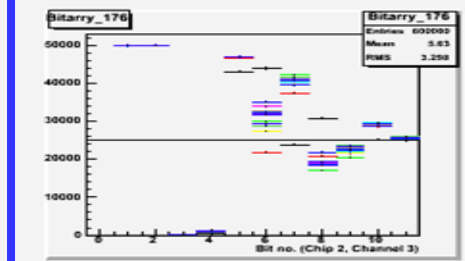
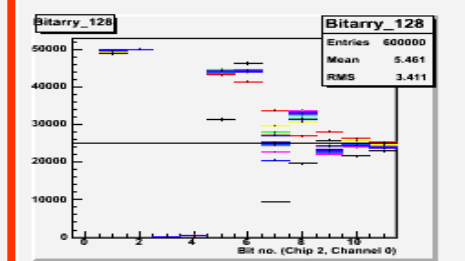
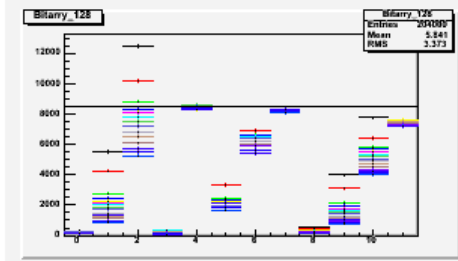
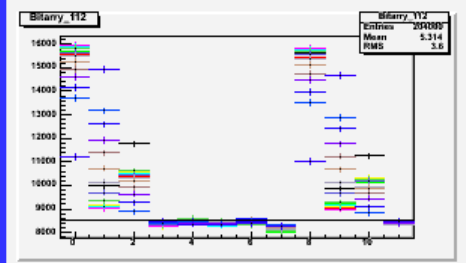
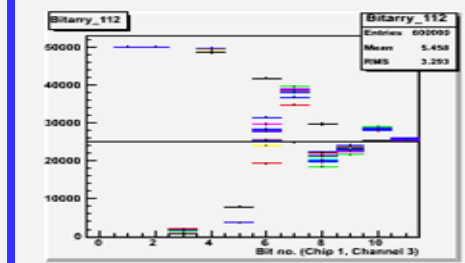
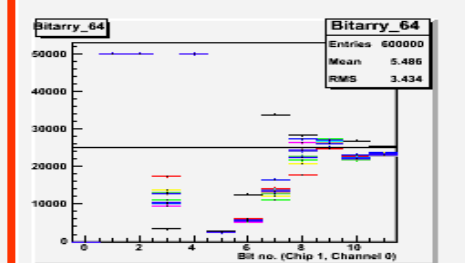
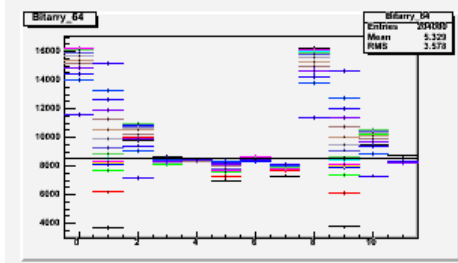
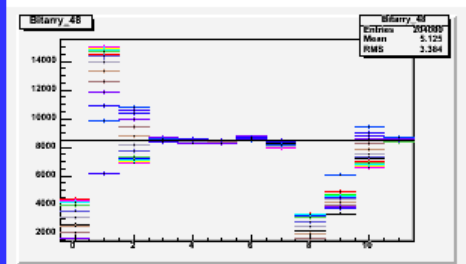
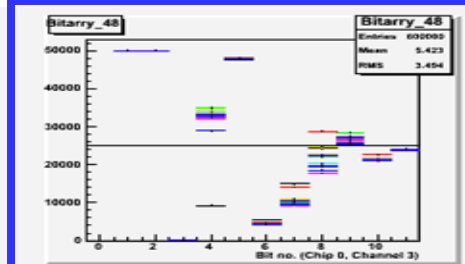
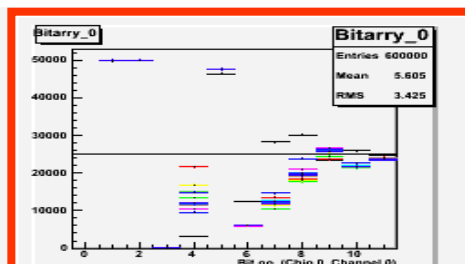
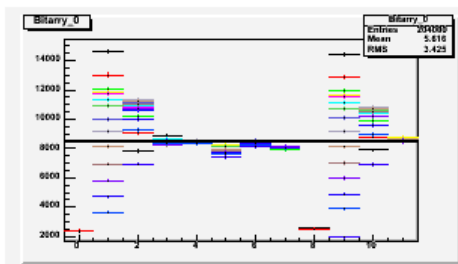
- Follow the usual steps



# Why lower S/N?



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testbeam

testbench

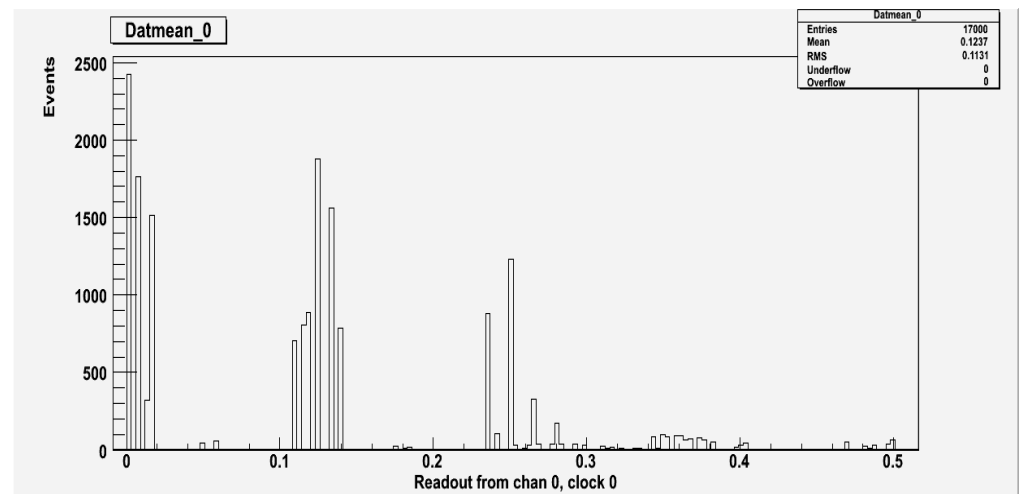
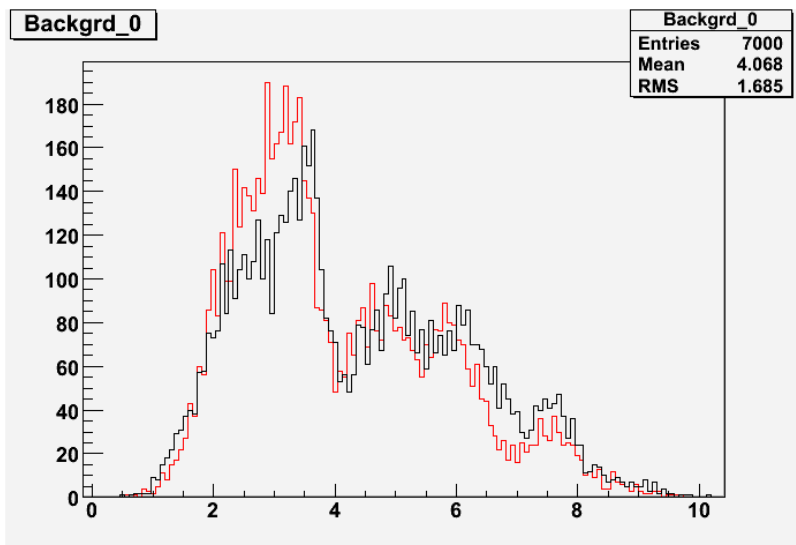
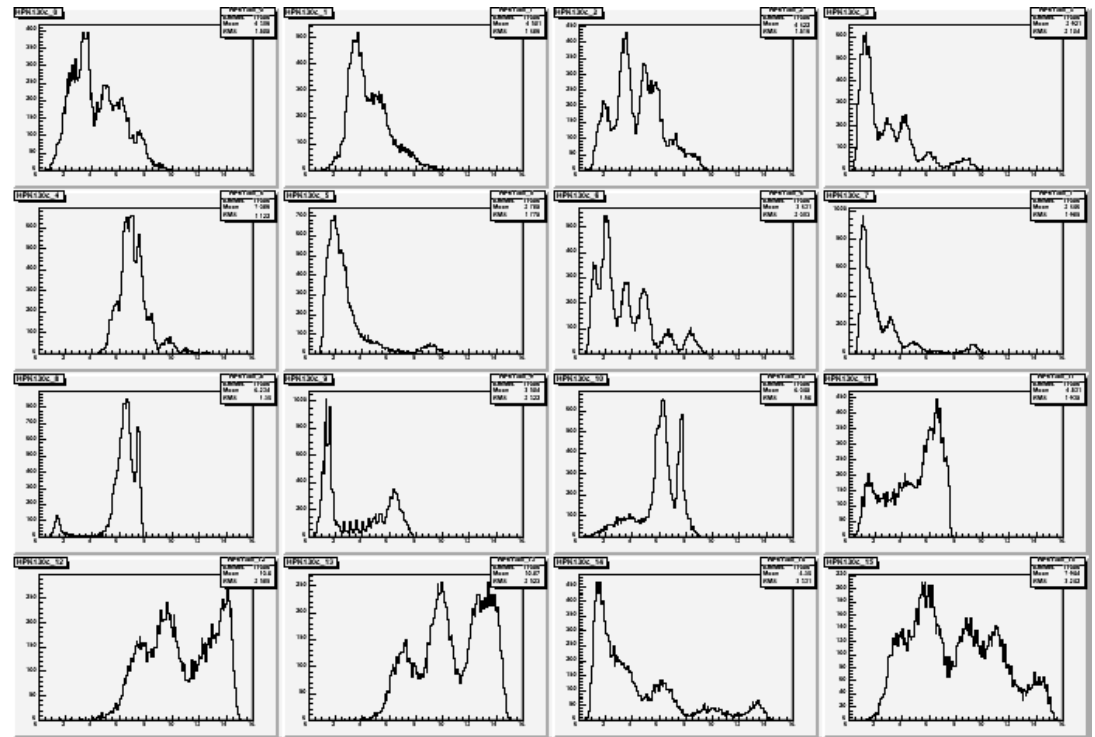
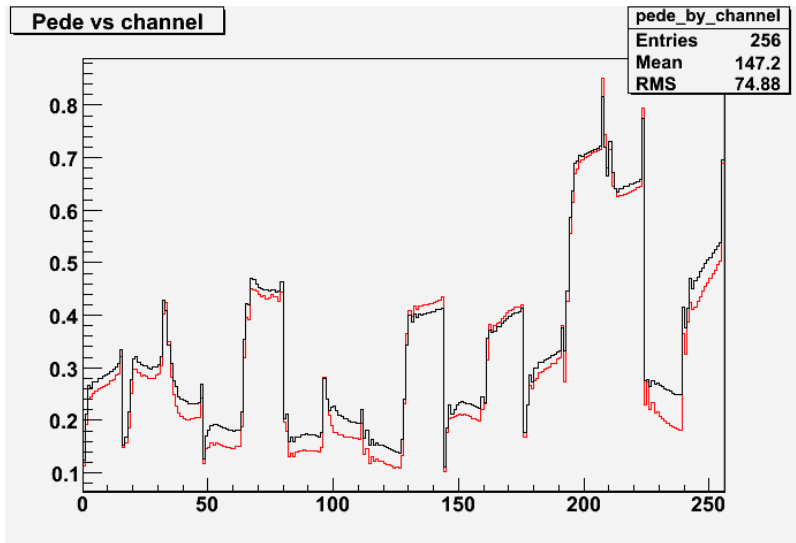
testbench

testbeam

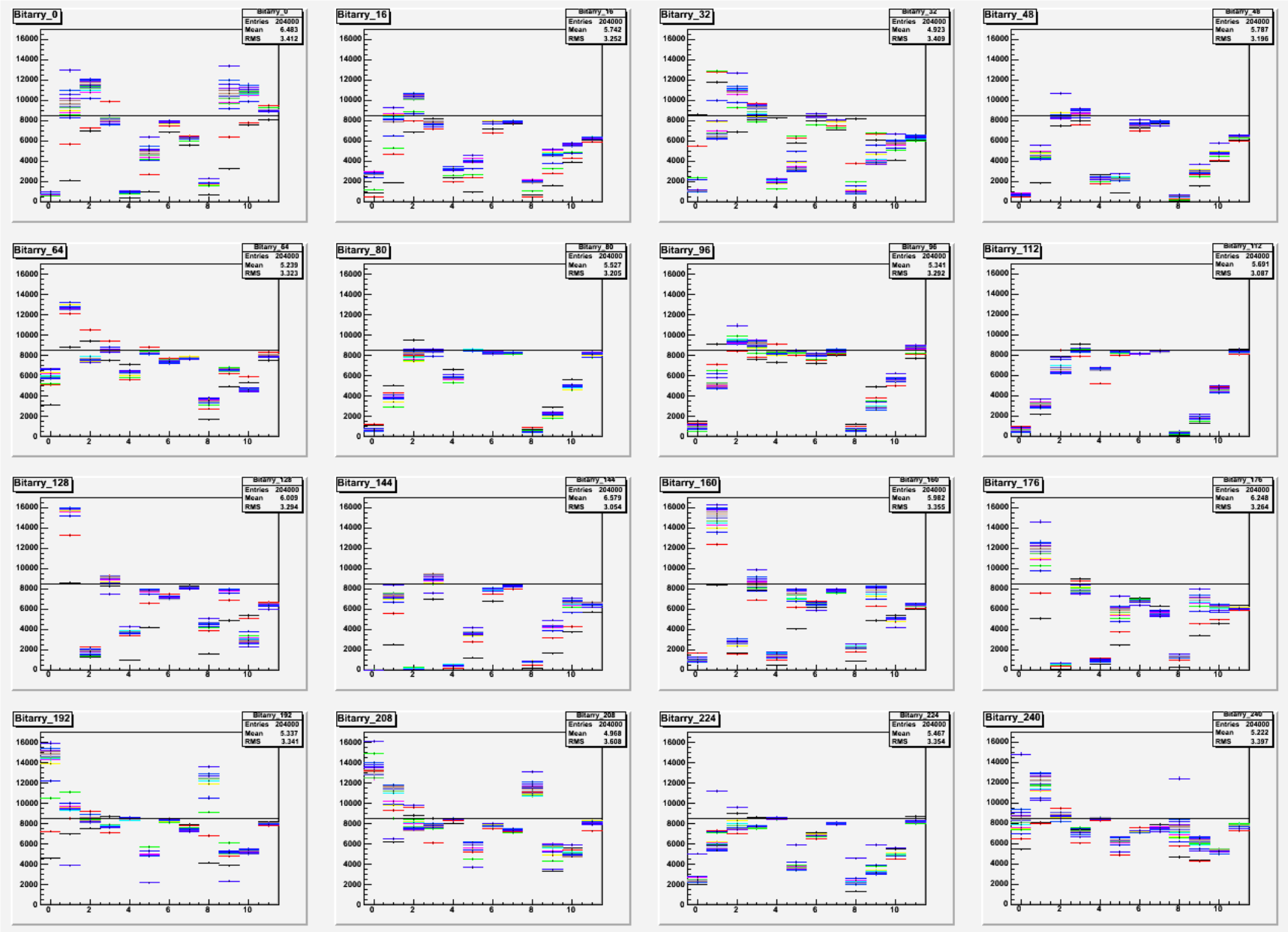


# CERN 07 testbeam (130 nm+hpk)

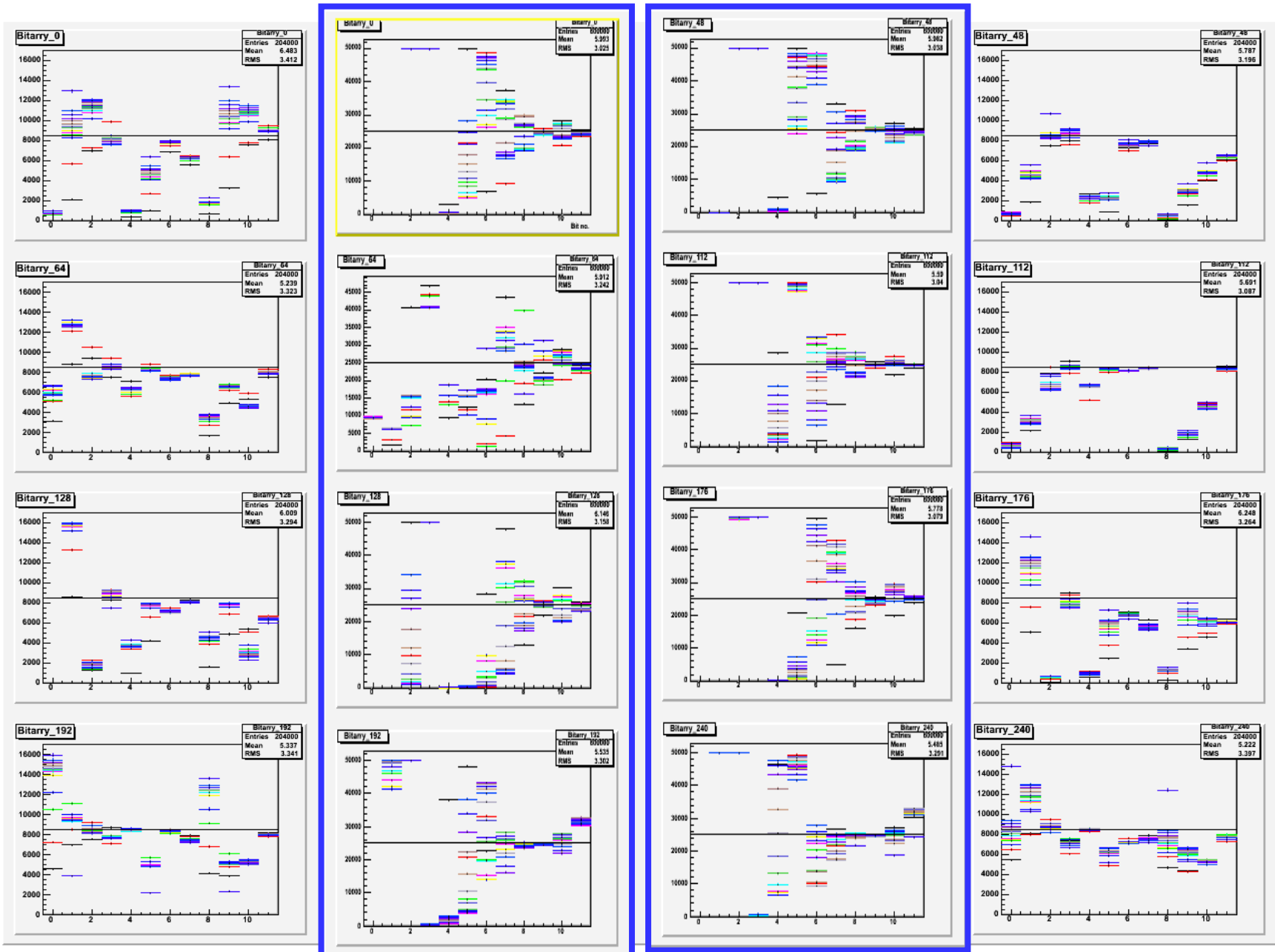
- Usual steps



# CERN 07 testbeam (130 nm+hpk)



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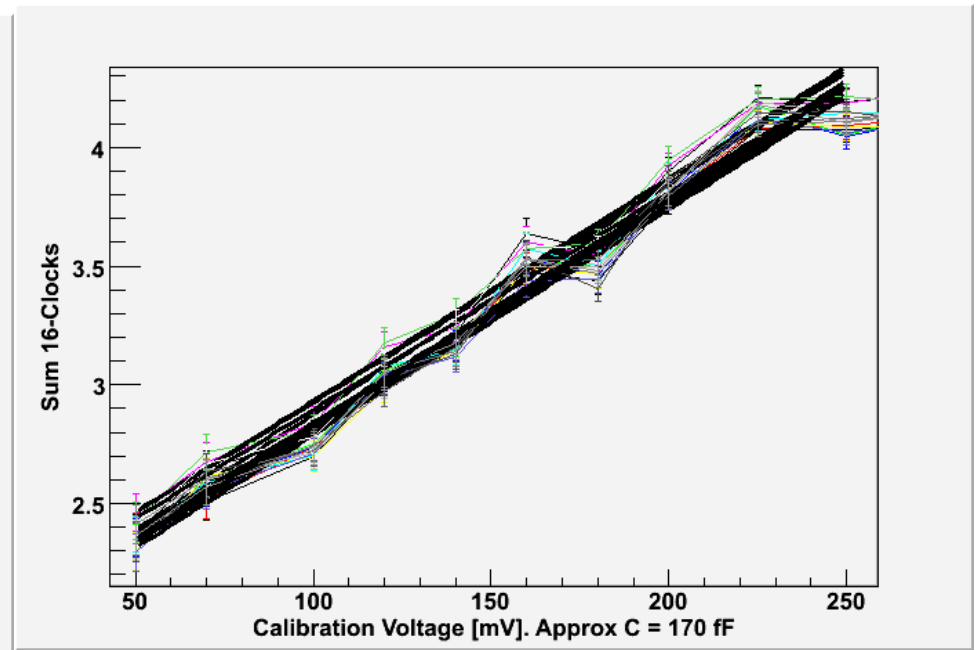
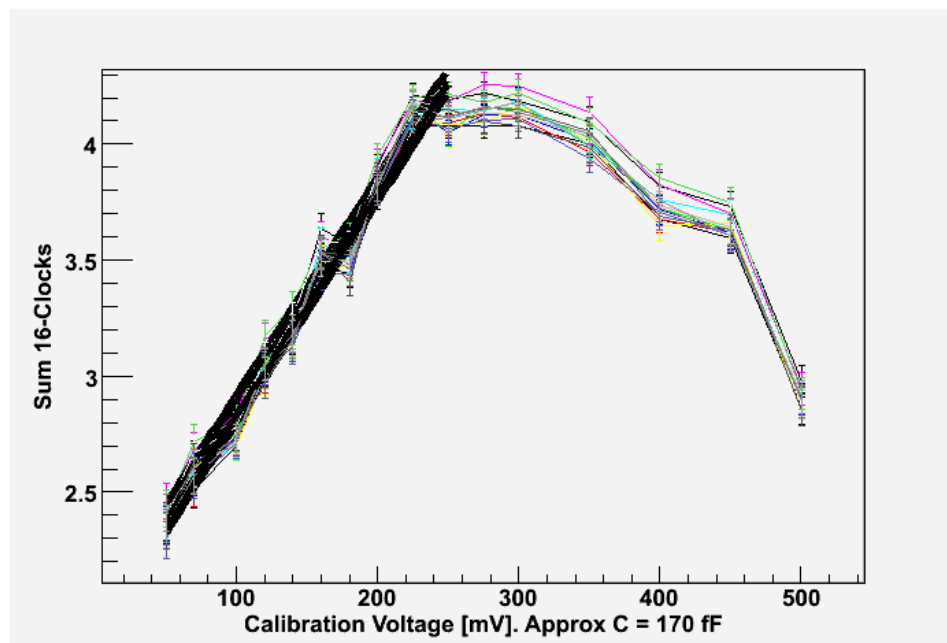


# Calibration studies 130 hpk

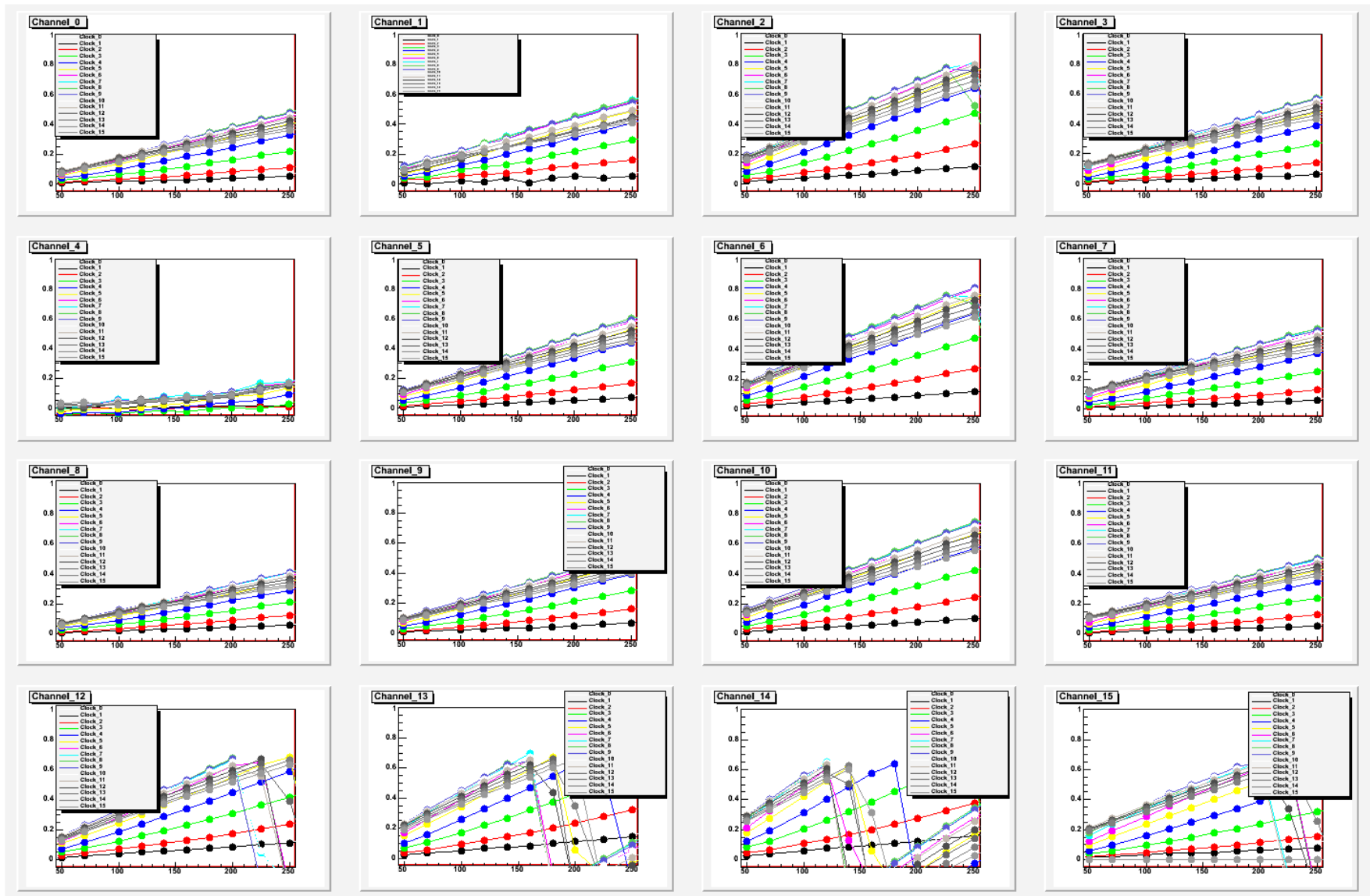
Testbench system

Varied Calibration voltage and monitored the readout (16-clock sum)

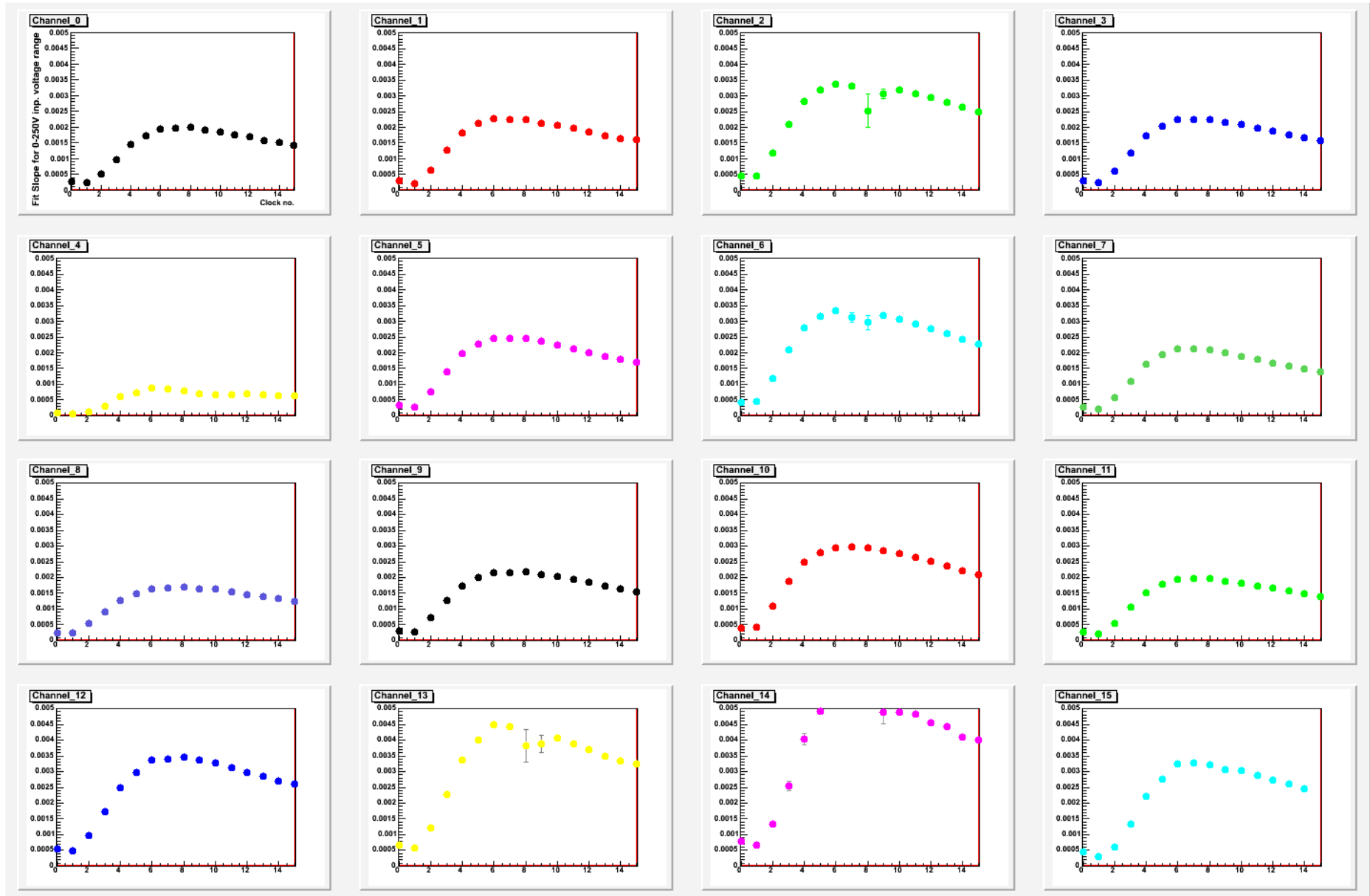
Linearity up to ~250 mV, at which points the chip saturates



# Calibration – fit vs channel view



# Calibration – slope vs channel view



# Conclusions

- New analysis of testbench and CERN data
- Simple now, more complex (yet user-friendlier) to come
- Calibration, testbench results check out well
- Mixed success, but good progress on CERN data
  - VA1 checks out
  - 130nmcms slightly better than 130nmhpk
    - Only a subset of the events can be recovered, different events for different channels.
- Deploy the new code so everybody gets to try it out:
- [lpnhe-lc.in2p3.fr/internal/](http://lpnhe-lc.in2p3.fr/internal/)

```
SenteriLC-insider  
tar-xzvf ...  
root  
.L apple_tree.c+  
readit2(4)
```

# Bit analysis

